

5-V Low-Drop Voltage Regulator

TLE 4275

Preliminary Data

Features

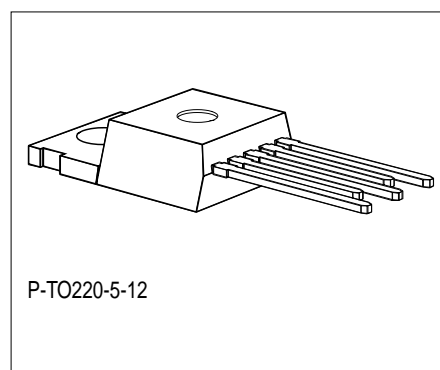
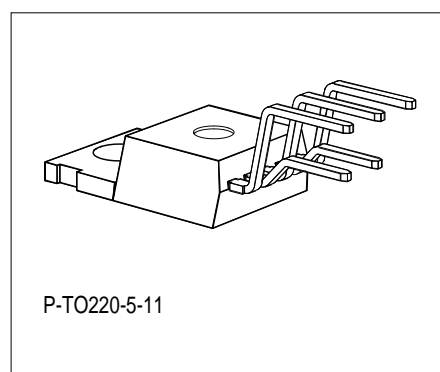
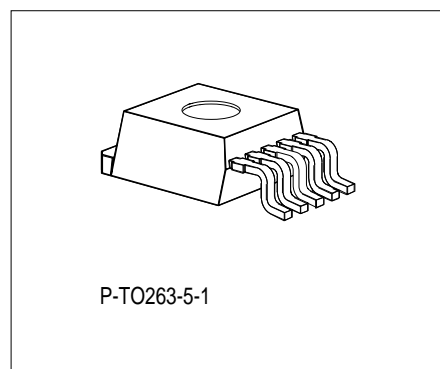
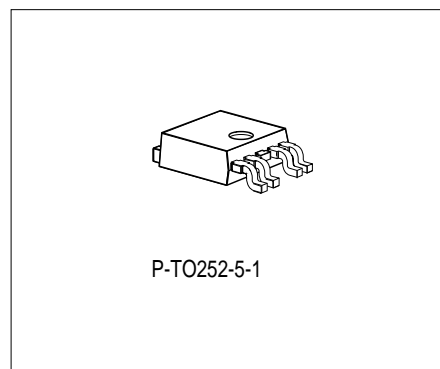
- Output voltage $5\text{ V} \pm 2\%$
- Very low current consumption
- Power-on and undervoltage reset
- Reset low down to $V_Q = 1\text{ V}$
- Very low-drop voltage
- Short-circuit-proof
- Reverse polarity proof
- Suitable for use in automotive electronics

Type	Ordering Code	Package
▼ TLE 4275 D	Q67006-A9354	P-TO252-5-1 (SMD)
▼ TLE 4275 G	Q67006-A9343	P-TO263-5-1 (SMD)
▼ TLE 4275	Q67000-A9342	P-TO220-5-11
▼ TLE 4275 S	Q67000-A9442	P-TO220-5-12

▼ New type

Functional Description

The TLE 4275 is a monolithic integrated low-drop voltage regulator in a 5 pin TO-package. An input voltage up to 45 V is regulated to $V_Q = 5.0\text{ V}$. The IC is able to drive loads up to 450 mA and is short-circuit proof. At over temperature the TLE 4275 is disabled by the incorporated temperature protection. A reset signal is generated for an output voltage V_Q of typ. 4.65 V. The delay time can be programmed by the external delay capacitor.



Dimensioning Information on External Components

The input capacitor C_i is necessary for compensating line influences. Using a resistor of approx. 1Ω in series with C_i , the oscillating of input inductivity and input capacitance can be damped. The output capacitor C_o is necessary for the stability of the regulation circuit. Stability is guaranteed at values $C_o \geq 22 \mu\text{F}$ and an ESR of $\leq 5 \Omega$ within the operating temperature range.

Circuit Description

The control amplifier compares a reference voltage to a voltage that is proportional to the output voltage and drives the base of the series transistor via a buffer. Saturation control as a function of the load current prevents any oversaturation of the power element. The IC also incorporates a number of internal circuits for protection against:

- Overload
- Over-temperature
- Reverse polarity

Pin Configuration

(top view)

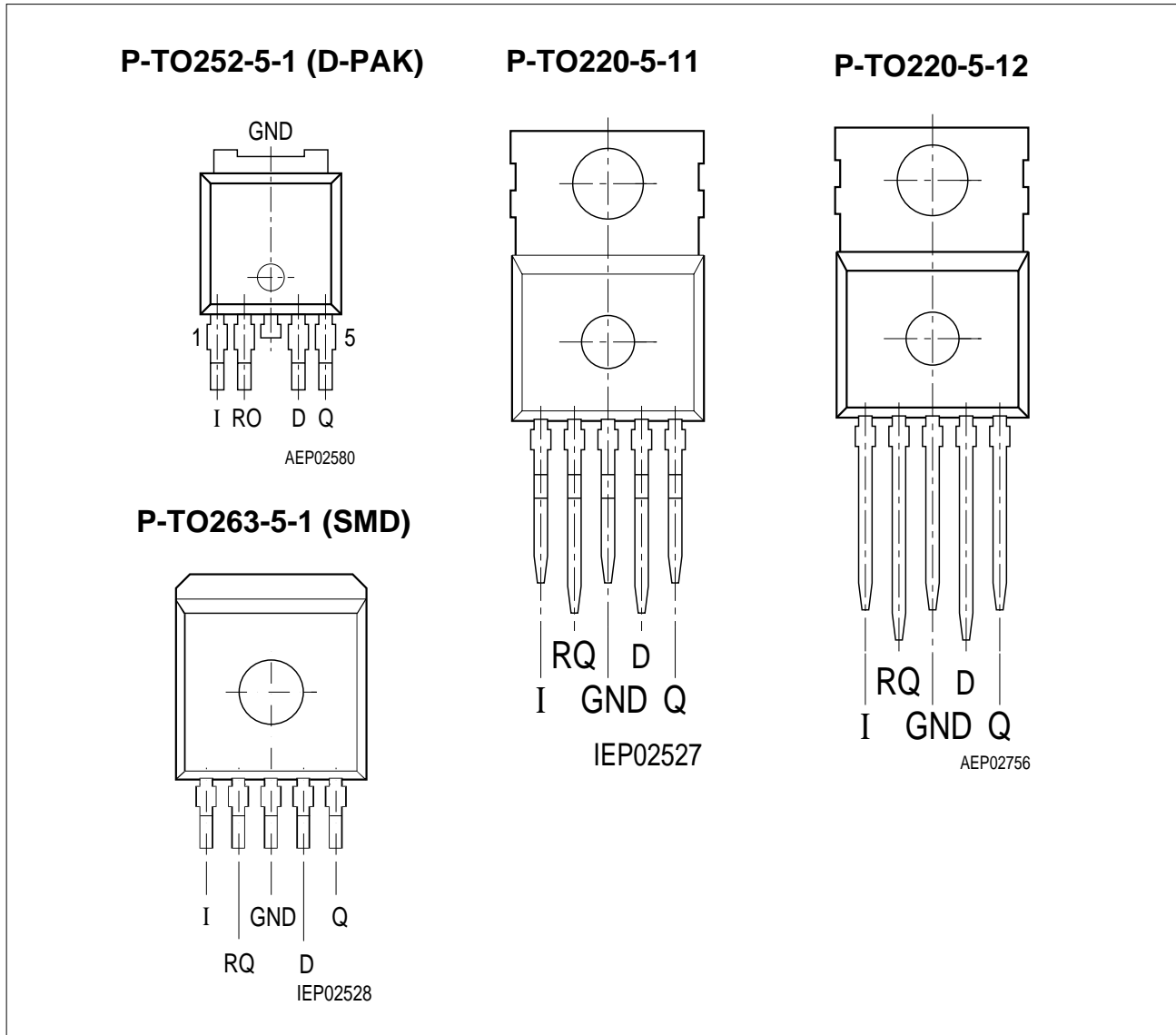


Figure 1

Pin Definitions and Functions

Pin No.	Symbol	Function
1	I	Input ; block to ground directly at the IC with a ceramic capacitor.
2	RQ	Reset Output ; open collector output
3	GND	Ground ; Pin 3 internally connected to heatsink
4	D	Reset Delay ; connected capacitor to GND for setting delay time
5	Q	Output ; block to ground with a $\geq 22 \mu\text{F}$ capacitor, ESR $< 5 \Omega$ at 10 kHz.

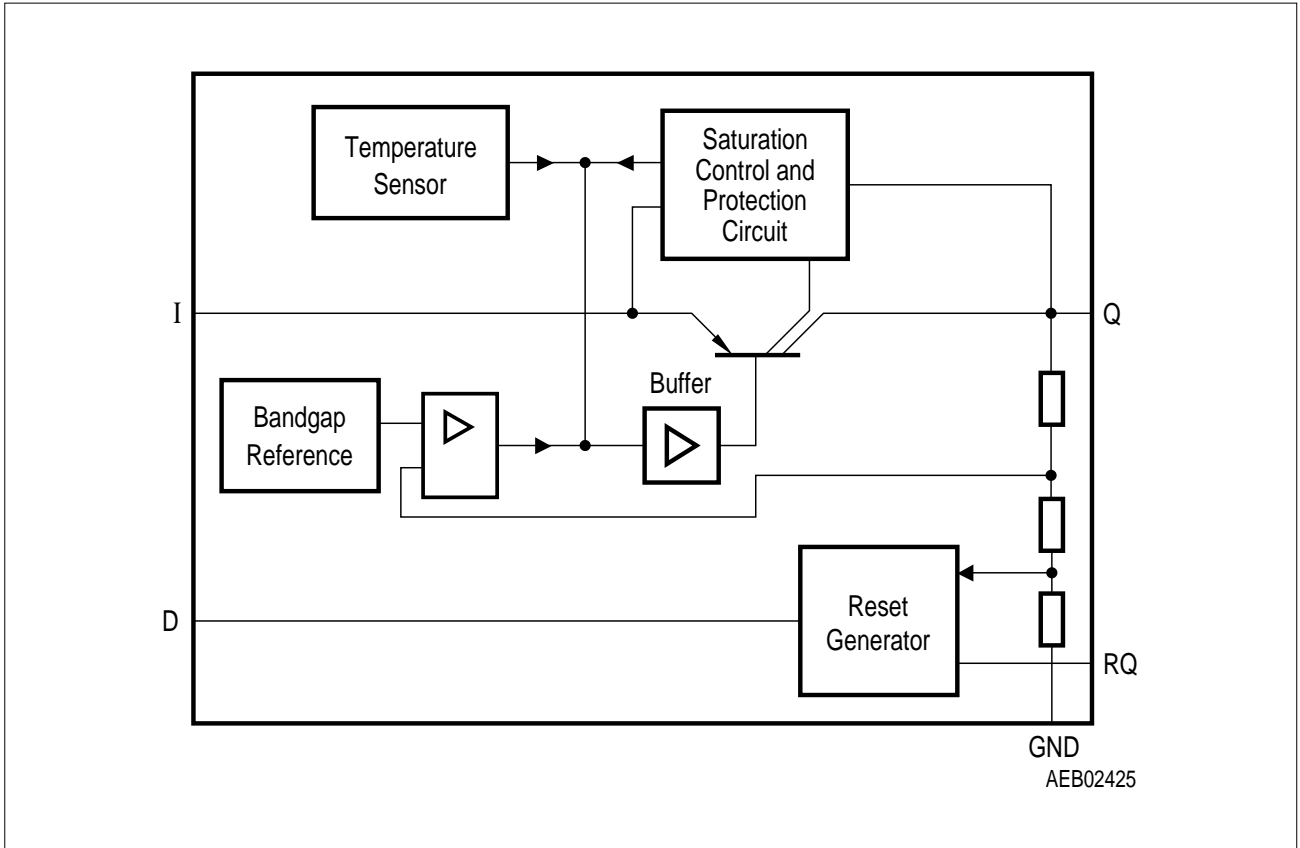


Figure 2
Block Diagram

Absolute Maximum Ratings
 $T_j = -40$ to 150 °C

Parameter	Symbol	Limit Values		Unit	Test Condition
		min.	max.		

Voltage Regulator
Input

Voltage	V_I	- 42	45	V	-
Current	I_I	-	-	-	Internally limited

Output

Voltage	V_Q	- 1.0	16	V	-
Current	I_Q	-	-	-	Internally limited

Reset Output

Voltage	V_{RO}	- 0.3	25	V	-
Current	I_{RO}	- 5	5	mA	-

Reset Delay

Voltage	V_D	- 0.3	7	V	-
Current	I_D	- 2	2	mA	-

Temperature

Junction temperature	T_j	-	150	°C	-
Storage temperature	T_{stg}	- 50	150	°C	-

Note: Maximum ratings are absolute ratings; exceeding any one of these values may cause irreversible damage to the integrated circuit.

Operating Range

Parameter	Symbol	Limit Values		Unit	Remarks
		min.	max.		
Input voltage	V_I	5.5	42	V	–
Junction temperature	T_j	– 40	150	°C	–

Thermal Resistance

Junction case	R_{thjc}	–	4	K/W	–
Junction ambient	R_{thja}	–	70	K/W	TO263
Junction ambient	R_{thja}	–	70	K/W	TO252 ¹⁾
Junction ambient	R_{thja}	–	65	K/W	TO220

1) Soldered in, minimal footprint

Characteristics

$V_I = 13.5 \text{ V}$; $-40 \text{ °C} < T_j < 150 \text{ °C}$ (unless otherwise specified)

Parameter	Symbol	Limit Values			Unit	Measuring Condition
		min.	typ.	max.		

Output

Output voltage	V_Q	4.9	5.0	5.1	V	$5 \text{ mA} < I_Q < 400 \text{ mA}$ $6 \text{ V} < V_I < 40 \text{ V}$
Output current limitation ¹⁾	I_Q	450	700	–	mA	–
Current consumption; $I_q = I_I - I_Q$	I_q	–	150	200	μA	$I_Q = 1 \text{ mA}$; $T_j = 25 \text{ °C}$
Current consumption; $I_q = I_I - I_Q$	I_q	–	150	220	μA	$I_Q = 1 \text{ mA}$; $T_j \leq 85 \text{ °C}$
Current consumption; $I_q = I_I - I_Q$	I_q I_q	–	5 12	10 22	mA mA	$I_Q = 250 \text{ mA}$ $I_Q = 400 \text{ mA}$
Drop voltage ¹⁾	V_{dr}	–	250	500	mV	$I_Q = 300 \text{ mA}$ $V_{dr} = V_I - V_Q$
Load regulation	ΔV_Q	–	15	30	mV	$I_Q = 5 \text{ mA to } 400 \text{ mA}$
Line regulation	ΔV_Q	– 15	5	15	mV	$\Delta V_I = 8 \text{ V to } 32 \text{ V}$ $I_Q = 5 \text{ mA}$

Characteristics (cont'd)

$V_i = 13.5\text{ V}$; $-40\text{ }^\circ\text{C} < T_j < 150\text{ }^\circ\text{C}$ (unless otherwise specified)

Parameter	Symbol	Limit Values			Unit	Measuring Condition
		min.	typ.	max.		
Power supply ripple rejection	$PSRR$	–	60	–	dB	$f_r = 100\text{ Hz}$; $V_r = 0.5\text{ Vpp}$
Temperature output voltage drift	$\frac{dV_Q}{dT}$	–	0.5	–	mV/ K	–

Reset Timing D and Output RQ

Reset switching threshold	V_{RT}	4.5	4.65	4.8	V	–
Reset output low voltage	V_{RQL}	–	0.2	0.4	V	$R_{ext} \geq 5\text{ k}\Omega$; $V_Q > 1\text{ V}$
Reset output leakage current	I_{RQH}	–	0	2	μA	$V_{RQH} > 4.5\text{ V}$
Reset charging current	I_d	3	6	9	μA	$V_D = 1\text{ V}$
Upper timing threshold	V_{DU}	1.5	1.8	2.2	V	–
Lower timing threshold	V_{DL}	0.2	0.4	0.7	V	–
Reset delay time	t_d	10	16	22	ms	$C_D = 47\text{ nF}$
Reset reaction time	t_{RR}	–	0.5	2	μs	$C_D = 47\text{ nF}$

1) Measured when the output voltage V_Q has dropped 100 mV from the nominal value obtained at $V_i = 13.5\text{ V}$.

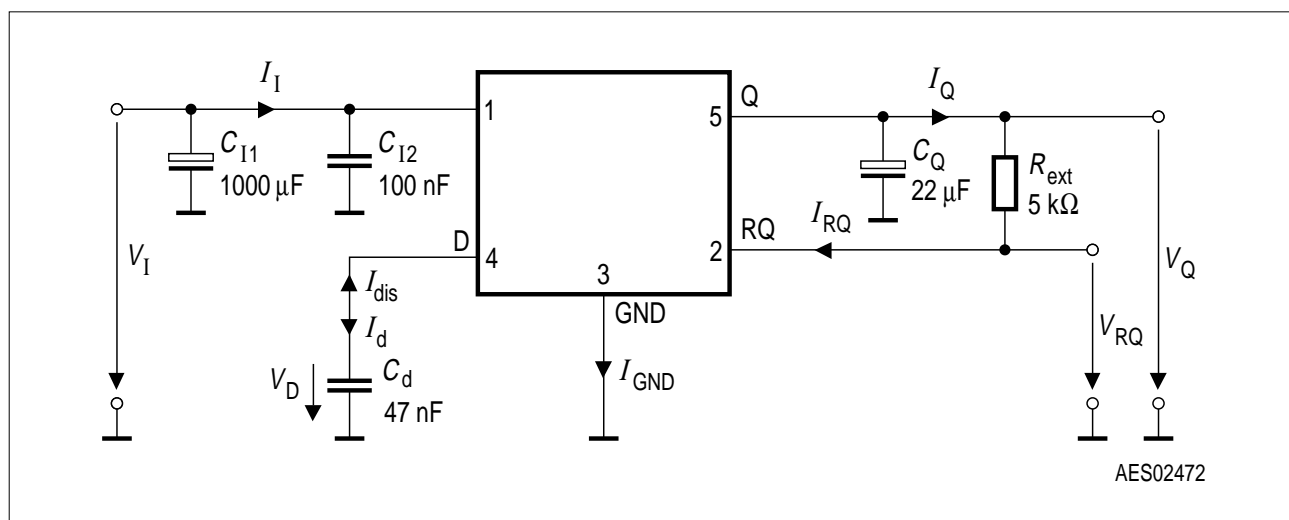


Figure 3

Test Circuit

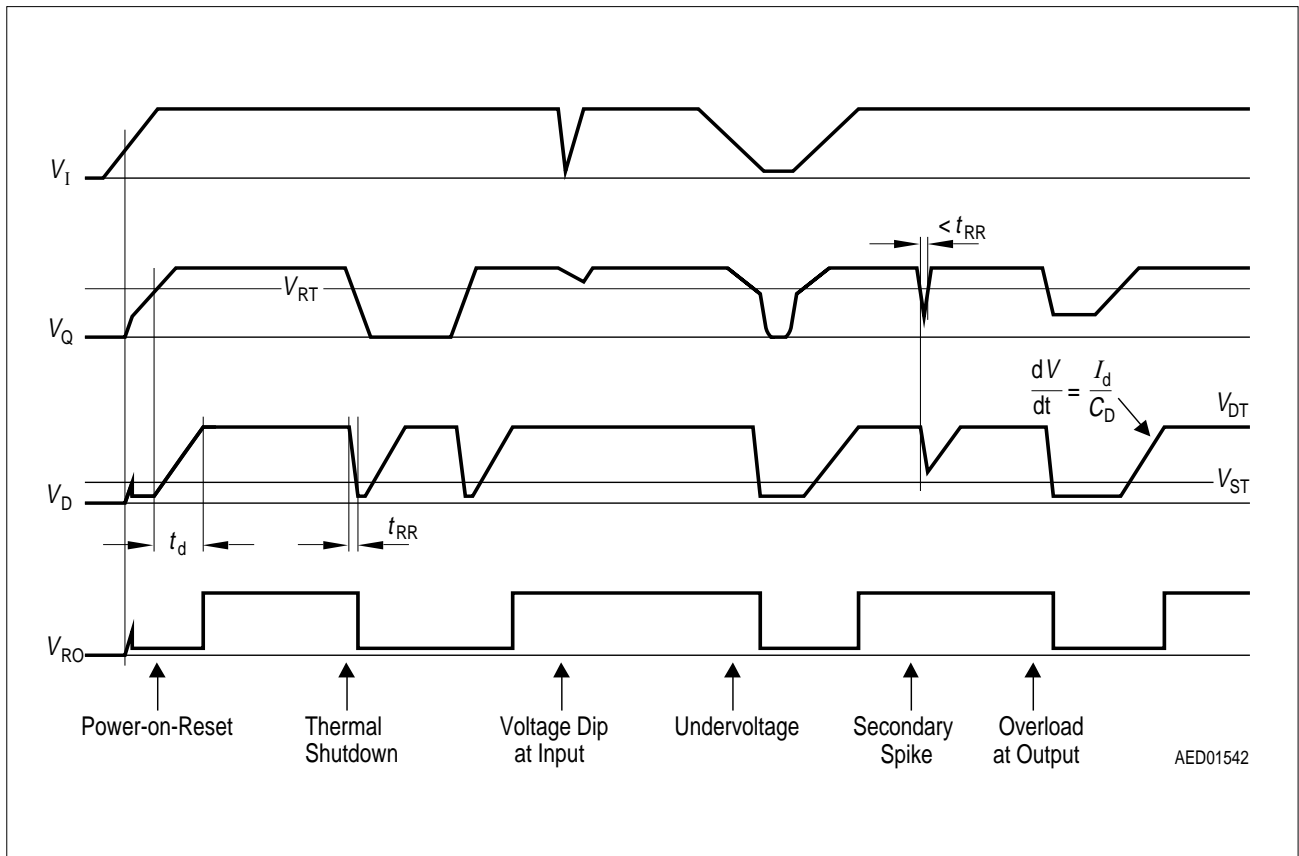
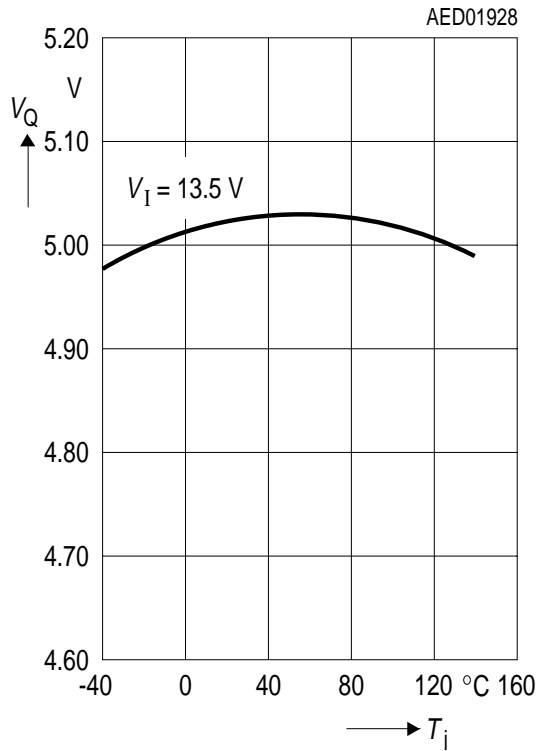
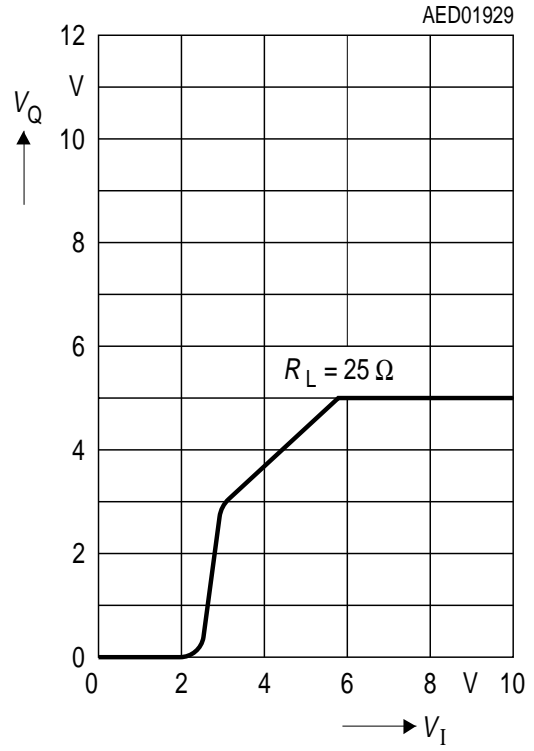


Figure 4
Reset Timing

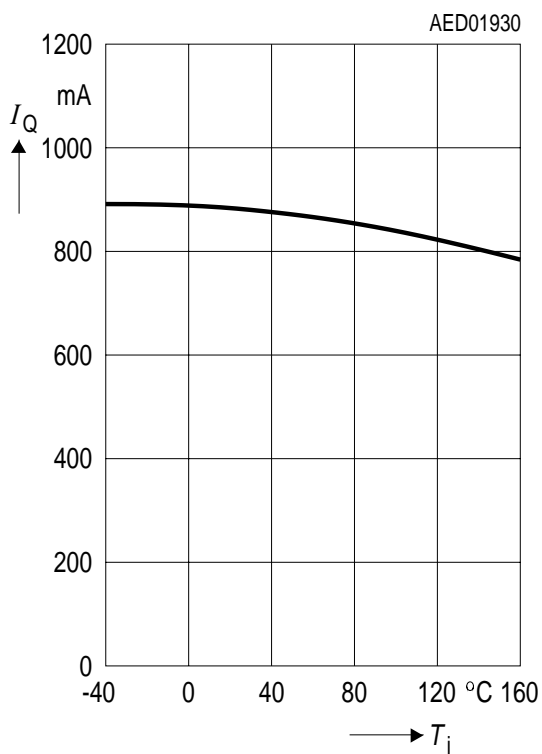
Output Voltage V_Q versus Temperature T_j



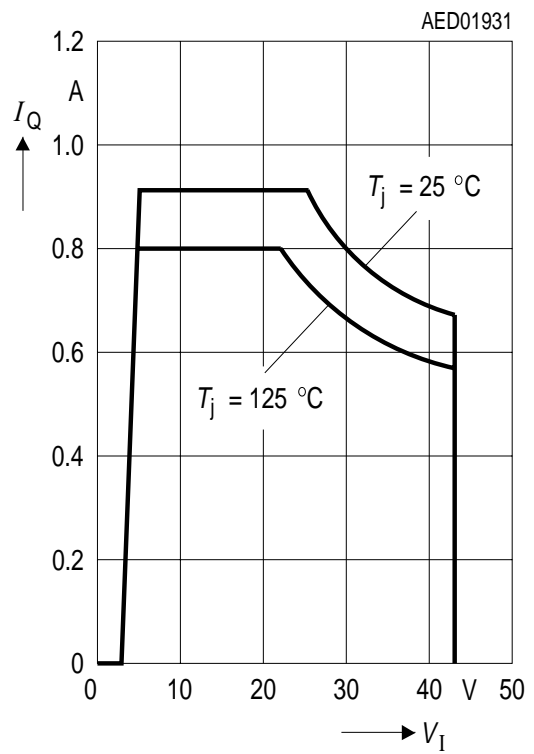
Output Voltage V_Q versus Input Voltage V_I



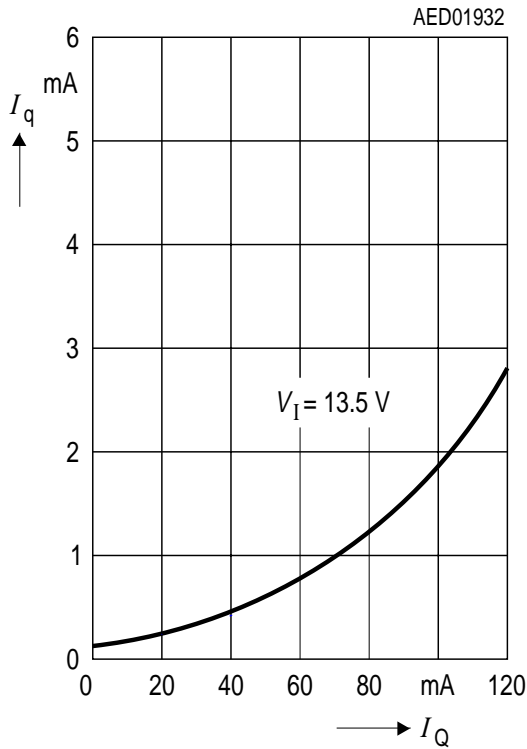
Output Current I_Q versus Temperature T_j



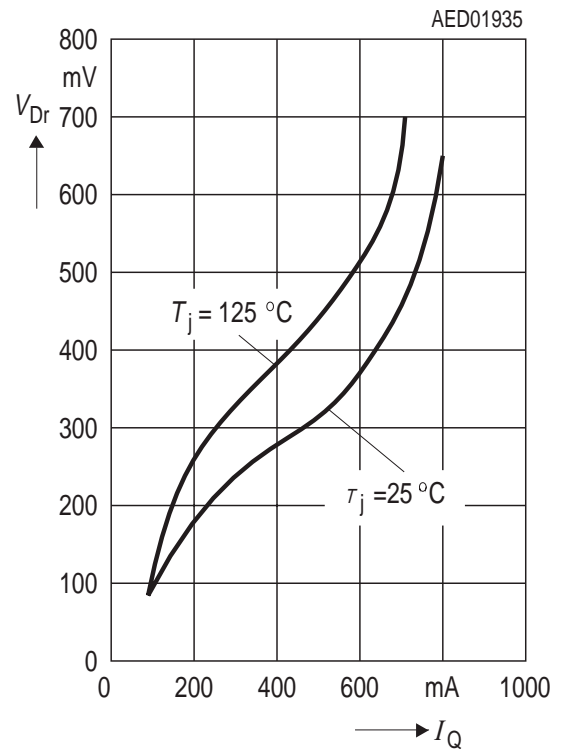
Output Current I_Q versus Input Voltage V_I



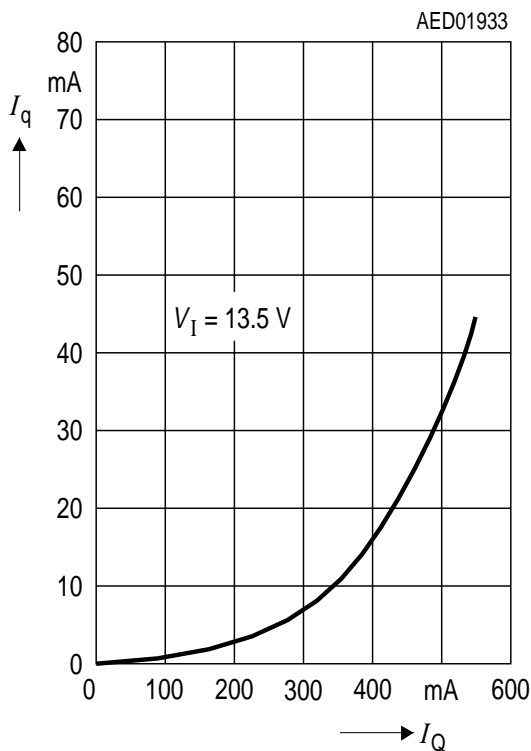
Current Consumption I_q versus Output Current I_Q



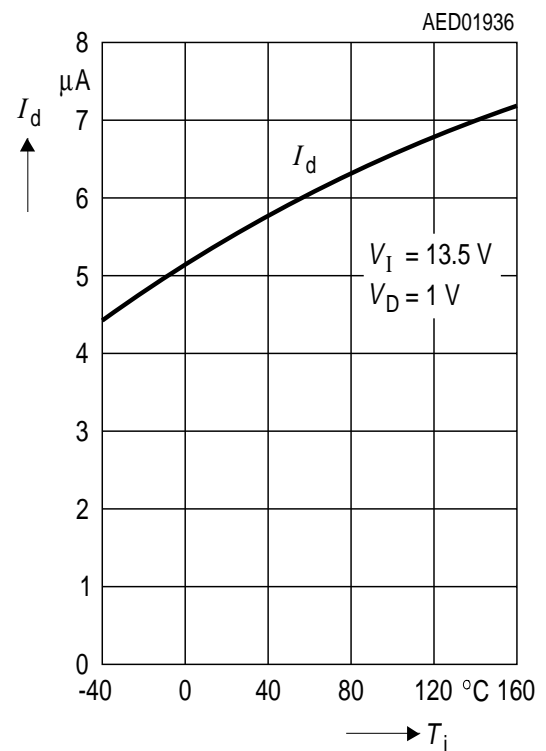
Drop Voltage V_{Dr} versus Output Current I_Q



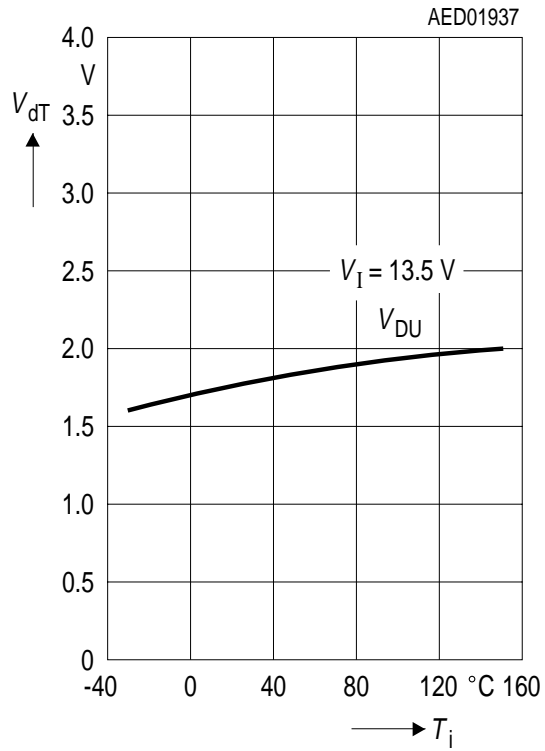
Current Consumption I_q versus Output Current I_Q



Charge Current I_d versus Temperature T_j

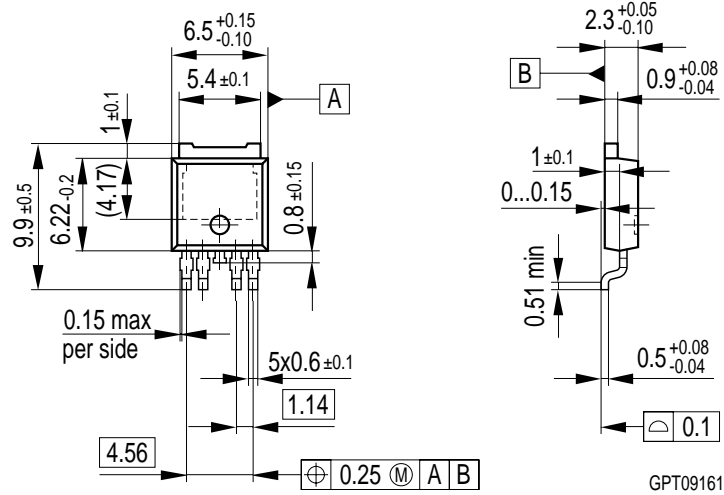


**Delay Switching Threshold V_{DU}
versus Temperature T_j**



Package Outlines

P-TO252-5-1 (D-PAK)
(Plastic Transistor Single Outline)



All metal surfaces tin plated, except area of cut.

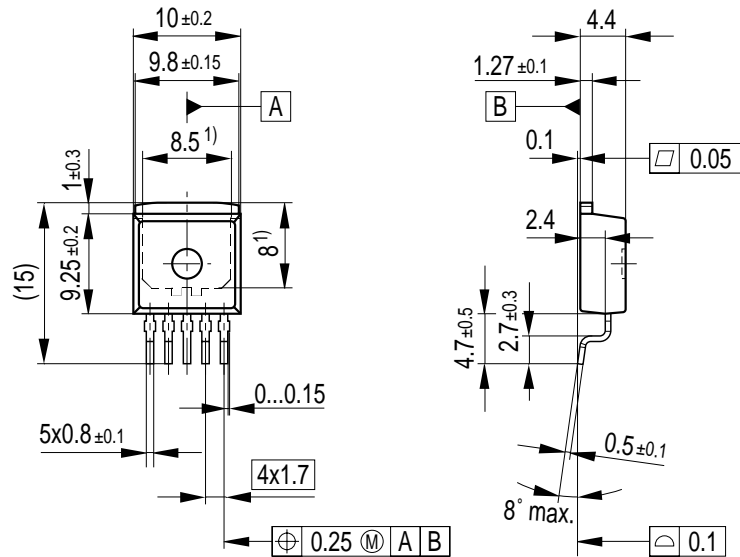
Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

SMD = Surface Mounted Device

Dimensions in mm

P-TO263-5-1 (SMD)
 (Plastic Transistor Single Outline)



1) Typical
 All metal surfaces tin plated, except area of cut.

GPT09113

Sorts of Packing

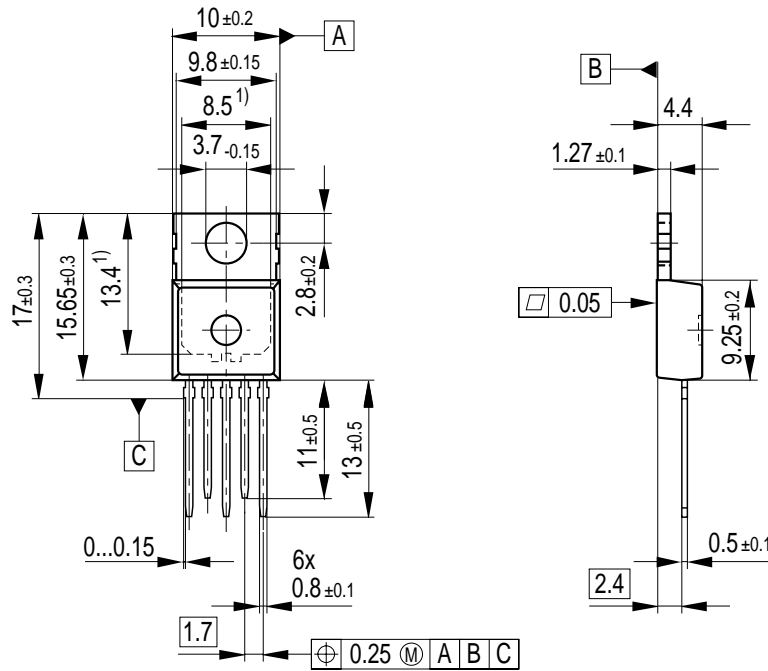
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SMD = Surface Mounted Device

Dimensions in mm

P-TO220-5-12

(Plastic Transistor Single Outline)



Typical

1) All metal surfaces tin plated, except area of cut.

GPT09065

Sorts of Packing

Package outlines for tubes, trays etc. are contained in our Data Book "Package Information".

Dimensions in mm

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